Resolution Effects on the Distribution of Current through a Resonant Level

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Current Distribution and Resolution



Noise Measurement Intrinsic information about the target system **Shot Noise** Low-energy excitation/interaction Johnson Noise Electric Temperature

How the resolution affects the current and noise?

Johnson Noise

Johnson-Nyquist (J-N) relation

$$S_I = 2k_B T G$$
$$S_V = 2k_B T R$$

Left: Current/Voltage Noise in equilibrium Right: Temperature x Conductance/Resistance

$$G = R^{-1} = \lim_{V \to 0} I/V$$

John B. Johnson, *Nature* **119**, 50 (1927); *Phys. Rev.* **32**, 97 (1928).

Harry Nyquist, *Phys. Rev.* **32**, 110 (1928).



Apparent Deviation from the expected value of Johnson noise at very low T.



м. Hashisaka, Y. Yamauchi, S. Nakamura, S. Kasai, K. Kobayashi, and T. Ono, *J. Phys.: Conf. Ser.* **109**, 012013 (2008).

Fluctuatioin-Dissipation Theorem

Deviations appear below 200 mK

Deviations at Early 1970's

R. A. Webb, R. P. Giffard, and J. C. Wheatley, J. Low. Temp. Phys. 13, 383 (1973).



Motivation

Johnson-Nyquist relation



ideal Can we obtain the intrinsic values by actual measurement devices, in principle? This problem is not clear!

"Resolution" has a close relation to the fact that we always have a smallest detectable change in every measurements.

Our Main Results

Limited Resolution does not affects the measured Current but, increases the measured Noise! *do not always satisfy the J-N relation*

Resonant level model (Single channel QPC with perfect transmission)



Limited resolution becomes a possible explanation of deviations

Resonant Level Model

Spinless Electrons



 $\hat{\mathcal{H}}(t) = \hat{H}_0 + \hat{V}(t)$ $\hat{H}_0 = \hat{H}_A + \hat{H}_B + \hat{H}_S$ Density matrix at t=0 $\hat{H}_{\rm A} = \sum \varepsilon_x^{\rm A} \hat{c}_x^{\dagger} \hat{c}_x$ $\hat{\rho}(0) = \frac{\mathrm{e}^{-\beta(\hat{H}_{\mathrm{A}}-\mu_{\mathrm{A}}\hat{N}_{A})}}{\mathrm{Tr}\left[\mathrm{e}^{-\beta(\hat{H}_{\mathrm{A}}-\mu_{\mathrm{A}}\hat{N}_{A})}\right]} \otimes \frac{\mathrm{e}^{-\beta(\hat{H}_{\mathrm{B}}-\mu_{\mathrm{B}}\hat{N}_{B})}}{\mathrm{Tr}\left[\mathrm{e}^{-\beta(\hat{H}_{\mathrm{B}}-\mu_{\mathrm{B}}\hat{N}_{B})}\right]} \otimes \hat{\rho}_{\mathrm{S}}(0)$ $x \in A$ $\hat{H}_{\rm B} = \sum \varepsilon_x^{\rm B} \hat{c}_x^{\dagger} \hat{c}_x$ $x \in \mathbf{B}$ $\hat{H}_{\rm S} = \varepsilon_0 \hat{d}^{\dagger} \hat{d}$ $\hat{V}(t) = \hat{V}_{\rm A}(t) + \hat{V}_{\rm B}(t)$ $\hat{V}_X(t) = \sum (t_X \theta(t) \hat{d}^{\dagger} \hat{c}_x + \text{H.c.})$ for X = A, B, $r \subset \mathbf{X}$

Model of Current Measurement: Two-point measurement model



 $I = e rac{dN}{d\mathcal{T}} \quad N$ is the particle number change of reservoir A during T. The probability that $\,N=k\Delta\,$ is given by k is a integer $\mathcal{P}(k;\mathcal{T},\Delta) = \text{Tr}[\sum \hat{M}_{k,l}^{\dagger}(\mathcal{T},\Delta)\hat{M}_{k,l}(\mathcal{T},\Delta)\hat{\rho}(0)]$ $\hat{M}_{k,l}(\mathcal{T},\Delta) = \hat{P}_{l+k}(\Delta)\hat{U}(\mathcal{T},0)\hat{P}_{l}(\Delta)$ Time evolution operator **Projection Operator**

Projection Operator

Projection Operator of a particle number measurement in reservoir A

$$\hat{P}_k(\Delta) \equiv \int_{\chi_k - \frac{\Delta}{2}}^{\chi_k + \frac{\Delta}{2}} dx \delta(x - \hat{N}_A)$$

Outcome

$$\chi_k \equiv \chi_0 + k\Delta$$

zero point deviation

 Δ means the smallest detectable change in the particle number measurement.



$$\Delta = 1 \quad \chi_0 = 0$$

M. Esposito, U. Harbola, and S. Mukamel, Rev. Mod. Phys. 81, 1665 (2009).

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Cumulant Generating Function

 $\mathcal{P}(k;\mathcal{T},\Delta) = \operatorname{Tr}[\hat{M}_{k}^{\dagger}(\mathcal{T},\Delta)\hat{M}_{k}(\mathcal{T},\Delta)\hat{\rho}(0)]$



$$\begin{split} \mathcal{C}(\lambda;\mathcal{T},\Delta) &\equiv \partial_{\mathcal{T}} \ln \left[\sum_{k} \mathrm{e}^{ik\lambda} \mathcal{P}(k;\mathcal{T};\Delta) \right] \quad \text{Cumulant Generating Function} \\ \mathcal{T}\Gamma \gg 1 \qquad \qquad \Gamma = 2\pi |t|^2 \sigma_0 \\ &\sim \partial_{\mathcal{T}} \ln \left[\sum_{m} \frac{\sin(\frac{\lambda+2\pi m}{2})}{\frac{\lambda+2\pi m}{2}} \exp[i\frac{\delta}{\Delta}2\pi m + \mathcal{T}\mathcal{C}_0(\frac{\lambda+2\pi m}{\Delta})] \right] \end{split}$$

 $C_0(\lambda)$ is a Levitov-Lesovik type CGF obtained from Full Counting Statistics. L. S. Levitov and G. B. Lesovik, JETP Lett. 58, 230 (1993); arXiv cond-mat/9401004 (1994).

$$\begin{split} \delta &\equiv N_A^0 - \chi_0 \mbox{ mod } \Delta \\ & \mbox{ Initial particle } \\ & \mbox{ number of } \\ & \mbox{ reservoir A } \end{split}$$

Degrees of Freedom of the initial density matrix within the resolution

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Cumulant Generating Function

 $\delta \equiv N_A^0 - \chi_0 \mod \Delta$ We cannot obtain the initial information practically

Random averaging (analogy of quenched random systems).

 $\langle \cdots \rangle_{\delta} \equiv \int_{0}^{\Delta} \frac{d\delta}{\Delta} \cdots$

$$\mathcal{C}(\lambda;\mathcal{T},\Delta) \equiv \partial_{\mathcal{T}} \langle \ln \left[\sum_{m} \frac{\sin(\frac{\lambda+2\pi m}{2})}{\frac{\lambda+2\pi m}{2}} \exp[i\frac{\delta}{\Delta}2\pi m + \mathcal{T}\mathcal{C}_{0}(\frac{\lambda+2\pi m}{\Delta})] \right] \rangle_{\delta}$$

 $\Delta=1~$ We can distinguish electrons, one by one. $\mathcal{C}(\lambda;\mathcal{T},1)=\mathcal{C}_0(\lambda)$ Full Counting Statistics

Our quantum measurement scheme is an extension of FCS.

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Current and Noise

$$\begin{array}{lll} \text{Measured current} & I = I_0 \text{ Intrinsic} \leftarrow & \text{Full counting statistics} \\ \text{independent of } \mathcal{T} \Delta \\ \text{Measured noise} & S = S_0 + \langle \Delta S \rangle_\delta \\ & \text{Intrinsic} & \text{Excess noise} \\ S_0|_{V=0} = 2k_B T G_0 & \text{J-N relation is satisfied!} \\ \langle \Delta S \rangle_\delta \geq 0 & \text{Always positive} & G_0 \equiv \lim_{V \to 0} \partial I_0 / \partial V \\ & G \equiv \lim_{V \to 0} \partial I / \partial V = G_0 \end{array}$$

Johnson-Nyquist relation is not satisfied between S and G $\langle \Delta S \rangle_{\delta} \ge 0 \quad \Longrightarrow \quad S|_{V=0} \ge 2k_B T G$

Temperature Dependence



✓ Strong enhancement at very low temperatures
✓ Cannot be calibrated by usual empirical methods!

Deviation from J-N relation

Deviation from J-N relation between S and G



S

The deviation is enhanced and saturated at very low temperature

Measurable in experiment

Directly indicates the deviation

Saturated value of deviation

 $\sim \Lambda$

Delta Dependence



Excess noises are increased by increasing Delta.

T Dependence



$$\Delta = 10, \ \mathcal{T} = 10 \ \bigcirc \\ 10^2 \ \triangle \\ 10^3 \ \Box \\ 10^4 \ \bigtriangledown$$

Maximum Detectable Frequency of measurement device $\sim 1/\mathcal{T}$

Limitation of Frequency band of measurement device improves detectability of $\ S_0$

Single-parameter Scaling of Deviation



Summary

Resolution effects on Current Statistics arXiv:1307.7535

- ✓ Noise enhancement by limited resolution
- ✓ Deviation from Jonson-Nyquist relation
- ✓ Scaling behavior of deviation

Deviation From the Johnson-Nyquist Relation



✓ Consistent with experimental results

